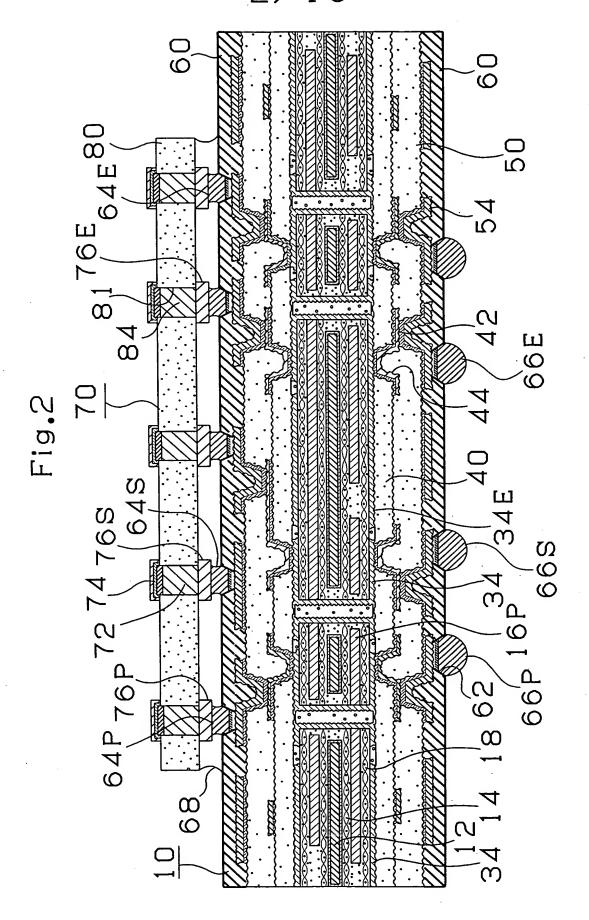


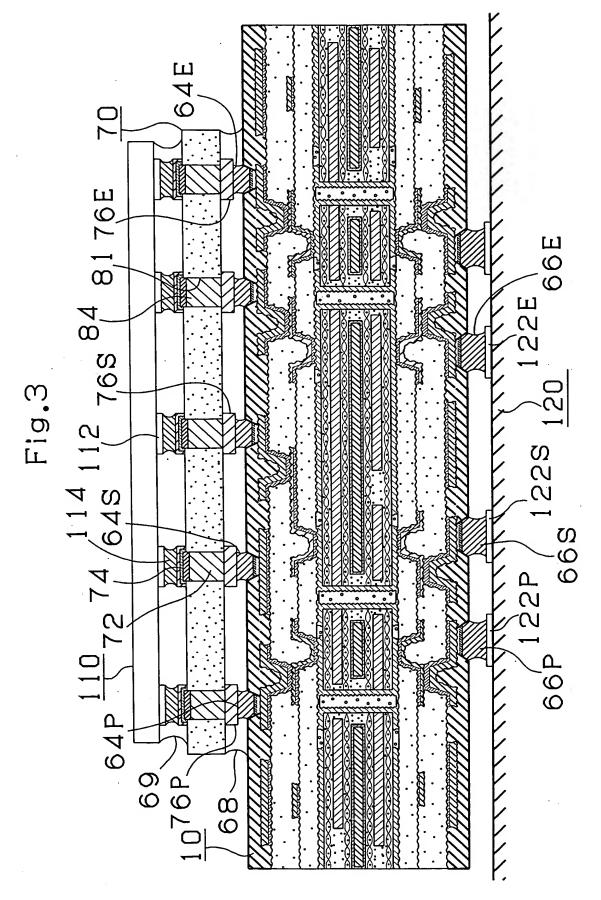
OBLON ET AL (703) 413-3000

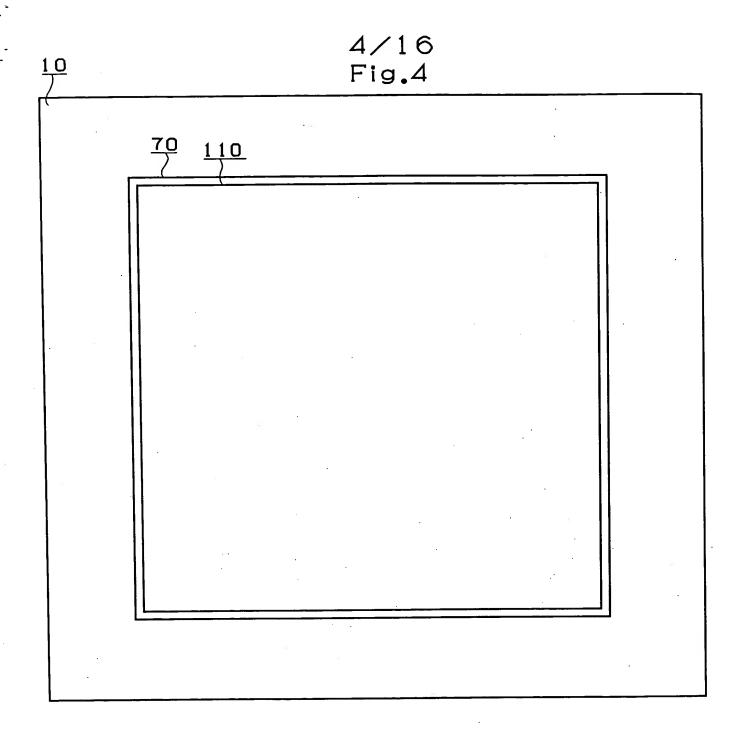
DOCKET # 28237/// S SHEET 2 OF 16

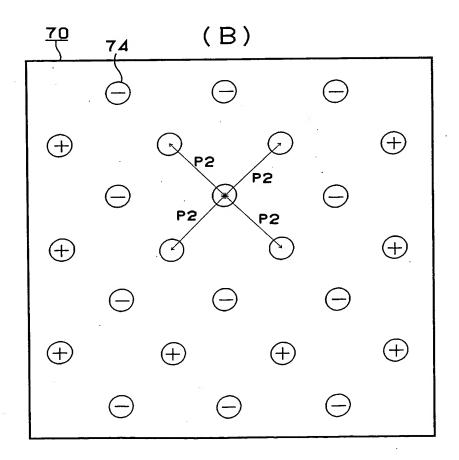
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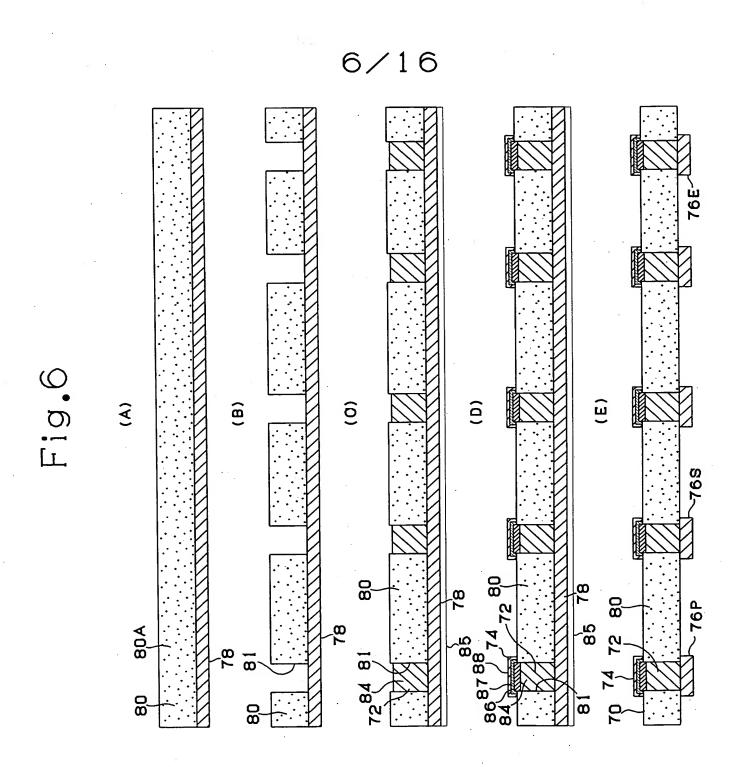


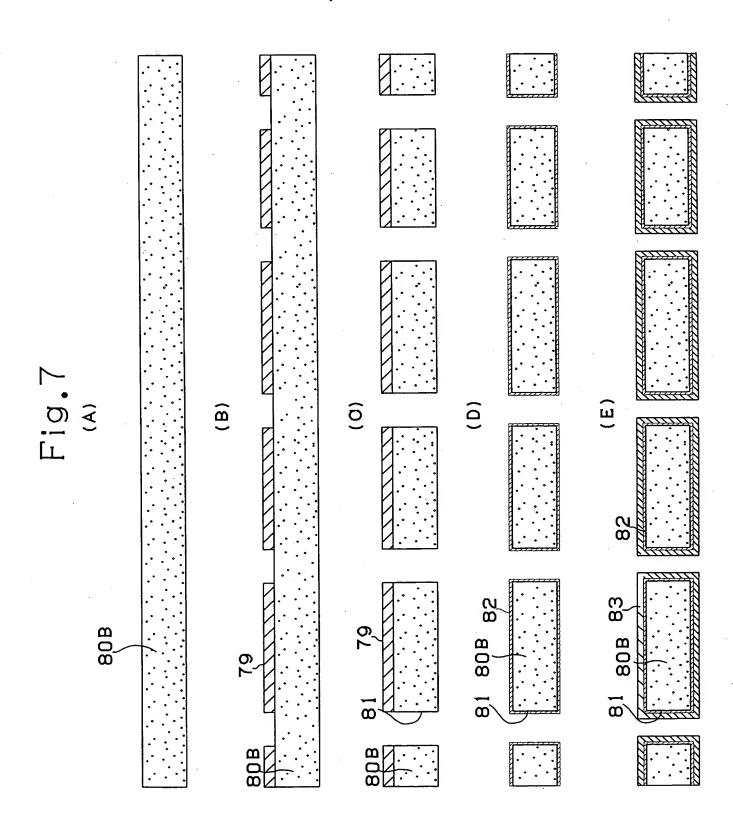
OBLON ET AL (703) 413-3000 DOCKET # 282371US SHEET 3 OF 16

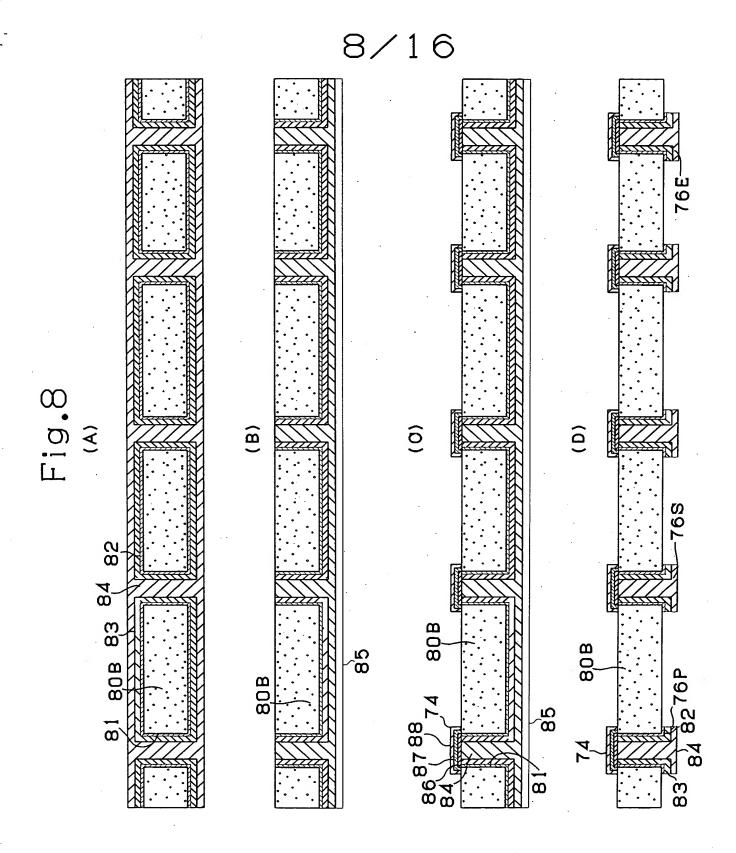


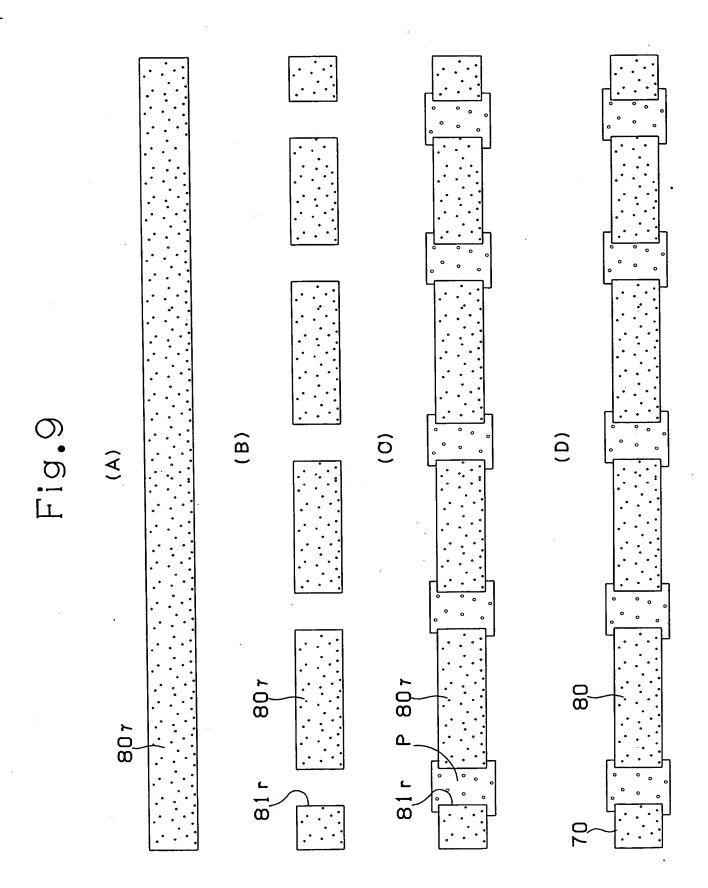


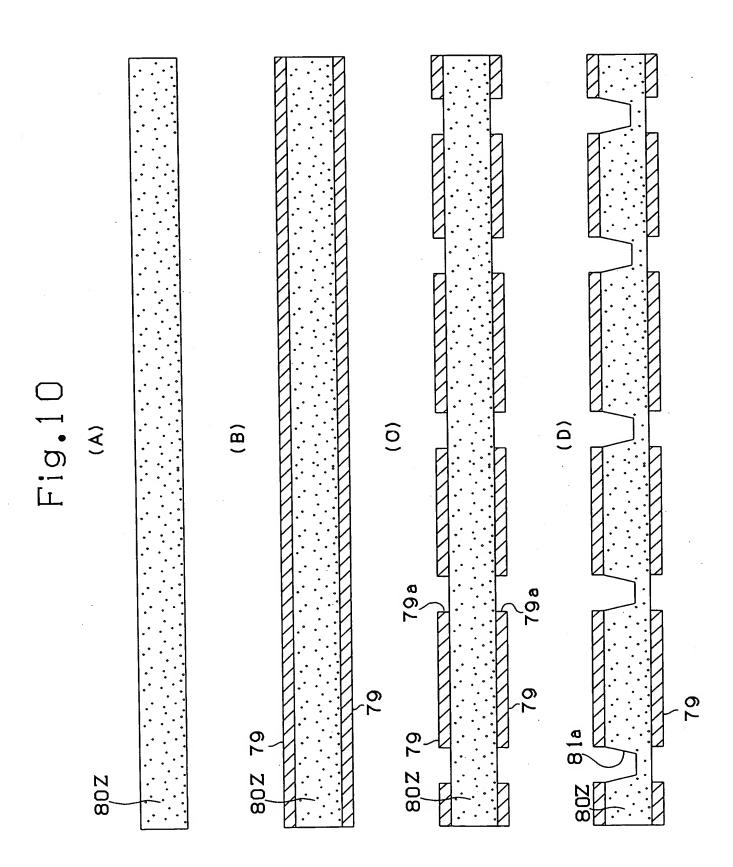


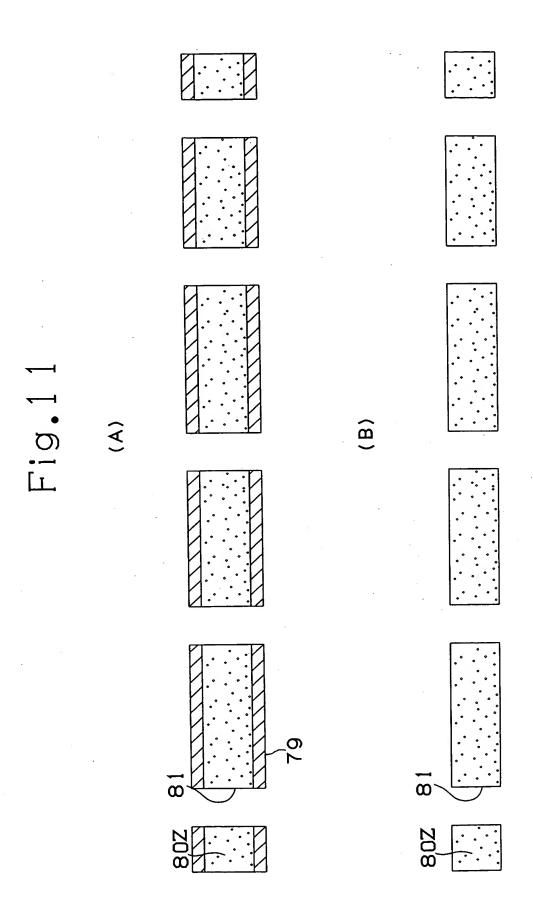












	Young's	Thickness of	Size of	Diameter of the	Diameter of through hole formed in insulation	in insulation	Change	amount of	Change amount of conduction	_
	modulus of	insulation base material	insulation	base material (µm)	(mrl)		resistano	e after he	resistance after heat cycle test (%)	st (%)
	hase	(11mt)	material	Diameter of	Diameter of	Diameter of	After	After	After	After
	material	ì	× mm)	opening in	opening in other	minimum	200	1000	1500	2000
	(Gpa)		mm)	an end face	end face	opening of through hole	cycles	cycles	cycles	cycles
Embodiment1	55	50	32	125	125	125	0	×	×	×
Embodiment2	55	64	32	125	125	125	0	۵	×	×
Embodiment3	55	100	32	125	125	125	0	0	×	×
Embodiment4	55	400	32	125	125	125	0	0	×	×
Embodiment5	55	1000	32	125	125	125	0	0	×	×
Embodiment6	55	1500	32	125	125	125	0	۵	×	×
Embodiment7	200	20	32	125	125	125	0	0	×	×
Embodiment8	200	64	32	125	125	125	0	0	0	×
Embodiment9	200	100	32	125	125	125	0	0	0	0
Embodiment10	200	400	32	125	125	125	0	0	0	0
Embodiment11	200	1000	32	125	125	125	0	0	0	0
Embodiment12	200	1500	32	125	125	125	0	0	0	×
Embodiment13	440	20	32	125	125	125	0	0	×	×
Embodiment14	440	64	32	125	125	125	0	0	0	×
Embodiment15	440	100	32	125	125	125	0	0	0	0
Embodiment16	440	400	32	125	125	125	0	0	0	0
Embodiment17	440	1000	32	125	125	125	0	0	0	0
Embodiment18	440	1500	32	125	125	125	0	0	0	×
Embodiment 19	200	100	24	125	125	125	0	0	0	0
Embodiment20	200	100	20	125	125	125	0	0	×	×
Embodiment21	200	100	40	125	125	125	0	0	×	×
Embodiment22	310	400	32	125	125	125	0	0	×	×
Embodiment23	310	20	32	125	125	125	0	0	×	×
Embodiment24	310	64	32	125	125	125	0	0	0	×

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	Young's	Thickness	Size of	Diameter of	Diameter of through hole formed in	rmed in	Change amount of conduction	Change amount of conduction	f conduction	tion test(%)
	modulus of	of 	insulation	insulation ba	insulation base material (µm)		נמפופרמונר	3	,	
	Insulation	Insulation	pase							
	base	base	material	Diameter	Diameter of	Diameter of	After	After	After	After
	material	material	(mm x mm)	of opening	opening in	minimum	200	00 00 00 00	1200	2000
	(Gna)	(umt)		in an end	other end	opening of	cycles	cycles	cycles	cycles
				face	face	through				8
								,	,	
Embodiment25	310	100	32	125	125	125	0	0	0	0
Embodiment 26	310	400	32	125	125	125	0	0	0	0
Embodiment 27	310	1000	32	125	125	125	0	0	0	0
Embodiment 28	310	1500	32	125	125	125	0	0	0	×
Embodiment 29	55	50	32	125	125	125	0	0	×	×
Embodiment30	55	64	32	125	125	125	0	0	0	×
Embodiment31	55	100	32	125	125	125	0	0	0	0
Embodiment32	55	400	32	125	125	125	0	0	0	0
Embodiment33	55	1000	32	125	125	125	0	0	0	0
Embodiment34	55	1500	32	125	125	125	0	0	0	×
Embodiment35	65.5	20	32	125	125	125	0	0	×	×
Embodiment36	65.5	64	32	125	125	125	0	0	0	×
Embodiment37	65.5	100	32	125	125	125	0	0	0	0
Embodiment38	65.5	400	32	125	125	125	0	0	0	0
Embodiment39	65.5	1000	32	125	125	125	0	0	0	0
Embodiment40	65.5	1500	32	125	125	125	0	0	0	×
Embodiment41	65.5	20	32	125	125	122.5	0	0	0	0
Embodiment42	65.5	20	32	125	125	25.0	0	0	0	0
Embodiment43	65.5	20	32	125	125	25.0	0	0	0	0
Experimental Example 1	200	100	32	125	125	125	0	×	×	×
Experimental Example 2	200	100	32	125	125	125	0	0	0	0
Experimental Example3	200	100	32	90	09	09	0	0	0	×
Experimental Example4	200	100	32	09	09	09	0	0	0	×

	Young's modulus	Thickness of		Diameter of th insulation base	Diameter of through hole formed in insulation base material (μm)	ned in	Change amount of conduction resistance after heat cycle test (%)	ount of col after heat	nduction cycle test	%
	of	insulation	base material							
	insulation	_	(mm × mm)	Diameter of	Diameter of	Diameter of	After 500	After	After	After
	base			opening in	opening in	minimum	cycles	1000	1500	2000
	material	(µmt)		an end face	other end	opening of	•	cycles	cycles	cycles
	(Gpa)				face	through hole				
Comparative	50	100	32	125	125	125	×	×	×	×
Example1										
Comparative	470	100	32	125	125	125	×	×	×	×
Example2										
Comparative	200	45	32	125	125	125	×	×	×	×
Example3		. * !								
Comparative	200	1600	32	125	125	125	×	×	×	×
Example4										
Comparative	55	20	15	125	125	125	IC cannot be mounted on the insulation	be mounte	d on the i	nsulation
Example5	_						material.			
Comparative	55	20	45	125	125	125	Insulation material cannot be mounted	material c	annot be	mounted
Example6				-			on the package substrate.	kage subst	rate.	
Comparative	65.5	20	32	125	125	22.7	0	×	×	×
Example 7										

○ : -3% ≤ resistance change rate v 3%

 \bigcirc : -6% \leq resistance change rate < -3% and 3% < resistance change rate \leq 6%

X:-10% > resistance change rate and 10% < resistance change $\Delta~:$ -10% s resistance change rate < -6% and 6% < resistance change rate \le 10%

rate unacceptable if ±10% is exceeded

Thickness of package substrate: 1.0mm Resistance change rate (%) = I resistance value after heat cycle – initial value I/initial value x 100

Thickness of core of package substrate: 0.8mm External size of packag

External size of package substrate: 40mm x 40mm

External size of IC: 20mm x 20mm

